PC3SF11YVZA/ PC3SF11YVZB

■ Features

- 1. Isolation voltage between input and output (V_{iso (rms)}:5kV)
- High critical rate of rise of OFF-state voltage (dV/dt:MIN. 1 000V/μs)
- 3. Internal isolation distance (0.4mm or more)
- 4. Recognized by UL (File No. E64380)

Approved by VDE (VDE0884, File No.127413)

Approved by BSI (BS415, File No.6690,

BS7002, File No.7421)

Approved by SEMKO (File No.0033029/01-04)

Approved by DEMKO (File No.310107-01)

Approved by FIMKO (File No.15795)

* PC3SF11YVZA, PC3SF11YVZB are for 200V line

■ Applications

- 1. Home appliances
- 2. OA equipment, FA equipment
- 3. SSRs

■ Model Line-up

Minimum trigger current (Ift[MAX.])	for AC 200V line			
10mA	PC3SF11YVZA			
7mA	PC3SF11YVZB			

■ Absolute Maximum Ratings

Parameter		Symbol	Rating	Unit
Input	*1 Forward current	I_F	50	mA
	Reverse voltage	V_R	6	V
Output	*1 RMS ON-state current	IT (rms)	0.1	A
	Peak one cycle surge current	Isurge	1.2 (50Hz sine wave)	A
	Repetitive peak OFF-state voltage	V_{DRM}	600	V
*2 Isolation voltage		$V_{iso\;(rms)}$	5	kV
Operating temperature		Topr	-30 to +100	°C
Storage temperature		Tstg	-55 to +125	°C
	Soldering temperature	Tsol	260 (For 10s)	°C

^{*1} The derating factors of absolute maximum ratings due to ambient temperature are shown in Fig.1, 2

Reinforced Insulation Type Phototriac Coupler for Triggering

Outline Dimensions 2.54^{±0.25}

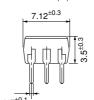
3SF11

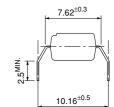
Anode

mark



(Unit: mm)





- Anode
 Cathode
- Anode, Cathode
- © Cair
- (5) No external connection
- 3 NC
- Anode, Cathode
- ₩ Pin ⑤ is not allowed external connection

1.2^{±0.3}

(Ta=25°C)

^{*2} AC for 1 min, 40 to 60%RH, f=60Hz

■ Electro	o-optical Chara	cteristics					(Ta=25°C)
Parameter			Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Input	Forward voltage		V_{F}	I _F =20mA	-	1.2	1.4	V
	Reverse current		IR	V _R =3V	_	_	10-5	A
Output	Repetitive peak OFF-state current		Idrm	$V_D = V_{DRM}$	_	_	10-6	A
	ON-state voltage		VT	I _T =0.1A	_	_	2.5	V
	Holding current		Iн	V _D =6V	0.1	_	3.5	mA
	Critical rate of rise of OFF-state voltage		dV/dt	$V_D=1/\sqrt{2} \cdot V_{DRM}$	1 000	2 000	_	V/µs
Transfer characteristics	Minimum trigger current	PC3SF11YVZA	I I I	V _D =6V, R _L =100Ω	_	-	10	
		PC3SF11YVZB			_	_	7	mA
	Isolation resistance		Riso	DC=500V, 40 to 60%RH	5×1010	1011	_	Ω
	Turn-on time		ton	V _D =6V, R _L =100Ω, I _F =20mA	_	-	100	μs

Fig.1 RMS ON-state Current vs. Ambient Temperature

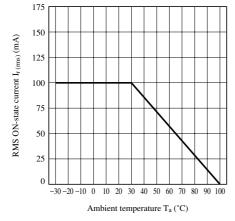


Fig.3 Forward Current vs. Forward Voltage

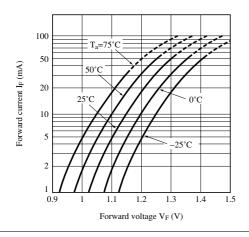


Fig.2 Forward Current vs. Ambient Temperature

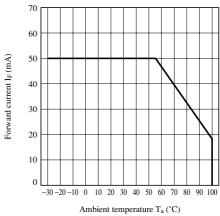


Fig.4 Minimum Trigger Current vs. Ambient Temperature

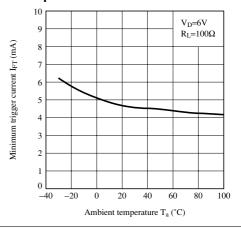


Fig.5 ON-state Voltage vs. Ambient Temperature

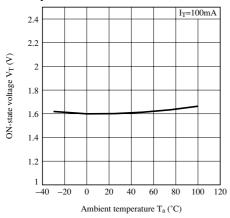


Fig.7 Repetitive Peak OFF-state Current vs. Ambient Temperature

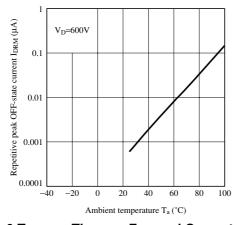


Fig.9 Turn-on Time vs. Forward Current

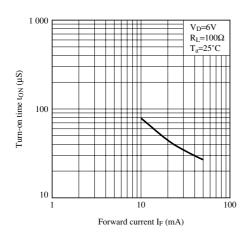


Fig.6 Holding Current vs. Ambient Temperature

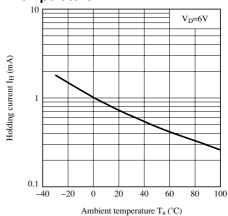
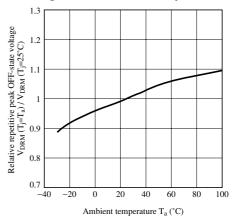


Fig.8 Relative Repetitive Peak OFF-state Voltage vs. Ambient Temperature



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 - --- Test and measurement equipment
 - --- Industrial control
 - --- Audio visual equipment
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